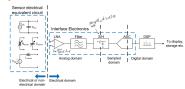
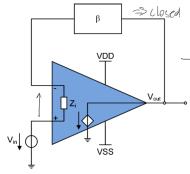
Sensor Principles

A generic sensor interface



OPAMP Basics

Opamps in feedback



Gain: $T(\omega) = \beta \cdot A_0(\omega)$

Phase Margin:

 $PM = 180^{\circ} + \angle (T(\omega_1)|_{|T(\omega_1)|=1}$ Gain $\mathsf{margin} : GM =$

 $20 \cdot log_{10}(rac{1}{T(\omega_2)})|_{\angle(T(\omega_2)=-180^\circ}$ Generic

Transfer function

 $V_x = \beta \cdot V_{\text{out}} = \beta \cdot A(\omega) \cdot (V_{\text{in}} - V_x) =$ $\beta \cdot A(\omega) \cdot (V_{\mathsf{in}} - \beta \cdot V_{\mathsf{out}})$

Feedback and linear operation

 $A(\omega) \gg 1 \Rightarrow$ virtual short at the input $\Delta V \approx 0$

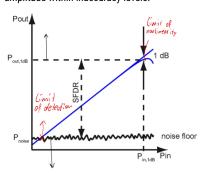
 $Z_i \to \infty \Rightarrow i_{oa} \approx 0$

Voltage Drive → negative feedback Current drive \rightarrow positive feedback

Errors and Noise

Limit of detection(LOD): minimum measurable input amplitude ($SNR \approx 0$)

Dynamic range()DR: ratio of max and min amplitude within inaccuracy levels.



Deterministic: source loading, offset, gain error Random: thermal noise. 1/f noise

Quantification:

Quantification: Absolute :
$$\Delta x = |\hat{x} - x_0|$$
 Relative: $\left|\frac{\Delta x}{x_0}\right| = \left|\frac{\hat{x} - x_0}{\hat{x}}\right|$ Max inaccuracy:

 $\Delta x_{max} | x \in [\hat{x} - \Delta x_{max}, \hat{x} + \Delta x_{max}]$

Error Propagation

 $y = f(x_1, x_2, \dots, x_N)$ Deterministic fluctuations of $x_i \rightarrow \text{total error}$: $\begin{array}{l} \Delta y \approx \sum_{i=1}^{N} \frac{\partial f}{\partial x_i} \cdot \Delta x_i \\ \text{Partial derivative } \frac{\delta f}{\delta x_i} \text{ is called } \textbf{sensitivity} \\ \text{Additive errors are best specified absolute and} \end{array}$

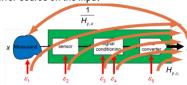
multiplicative errors are best specified relative Interference:

Unwanted coupling of external signal Noise: random fluctuations from setup \rightarrow can he modeled as error sources

Combining Error sources

Output referred noise

Effect of an error-source on the output Input referred noise Equivalent effect of the error-source on the input

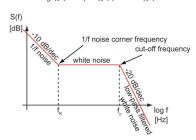


Find TF from ES to output

 $y:H_{y,ES}\Rightarrow y_{\mathrm{out}\,,\epsilon_2}=H_{y,\epsilon_2}\cdot\epsilon_2$ Refer result back to input wit $H_{y,x}: x_{\epsilon_2} = \frac{y_{\text{out},\epsilon_2}}{H_{y,x}} = H_{y,\epsilon_2} \cdot \frac{\epsilon_2}{H_{y,x}}$

Lin. System noise:

$$PSD = S_y(f) = |H(f)|^2 \cdot S_x(f)$$



Noise Types

Thermal noise: excitation of charge carriers(white)

Shot noise: carriers randomly crossing the barrier, dependent on DC bias and white Flicker Noise:, due to traps in semiconduct. 1/f

spectral density. MOS trans at low freq. Thermalnoise Theorem: Every closed system at temp. T has average. Energy of $kT/2 \rightarrow$ $S_{u}(f) = 2kTR(\text{ double-sided })$ math $S_u(f) = 4kTR($ single-sided) physics

Langevin Approach kt/C noise

PSD noise voltage of V_n $= S_{v_n}(f) = 4kT \cdot \Re\{Z(j2\pi f)\}$ $\rightarrow \overline{V_n^2} = kT \left[\frac{1}{C_\infty} - \frac{1}{C_0} \right] = \frac{kT}{C}$ MOS IRN

$$\begin{split} S_{\Delta V_{\text{nG-tot}}^2} &= 4kT \cdot R_{\text{nG-tot}} \,, \quad R_{\text{nG-tot}} = \\ \frac{\rho}{W \cdot L \cdot f} + \frac{\gamma_{nD}}{G_m} \, \text{with GateExcess Noise factor} \\ \vdots \\ \gamma_{nD} &= (n = 1.3) \cdot [0.5WI; 2/3SI] \end{split}$$

Bipolar Trans IRN:

 $S_{\Delta V_{nB}^2} = 4kT \cdot R_B$

Noise Aanalysis

small-signal-equivalent is valid. Total ORN:

S_{n, out}
$$(f) = \sum_{k=1}^{N} |H_k(f)|^2 \cdot S_{nk}(f)$$
 N uncorrelated NS.

 $H_{l\cdot}(f)$ TF from NS ton output. IRN:

$$S_{V_{\mathrm{neq,IRN}}}\left(f\right) = \frac{S_{V_{\mathrm{nout}}}\left(f\right)}{|A(f)|^{2}} \text{ with } A(f) \text{ is TF}$$

Sensor types

Information domain → Electrical domain Transduction: Converting a signal from the energy domain into another.

Sensors and actuators are transducers

Sources of eerror

Noise, sensitivity to unintended quantities,

$$\begin{bmatrix} E_{\rm exp} \\ E_{\rm min} \\ E$$

Tandem transducers: Multiple steps to target domain.

cross-sensitivity, sensitivity to undesired quantity

Sensor classification:

Active Sensors:

Require external source of excitation

Passive / self-generating sensors:

Generate their own electrical output signal Draws all required energy from the measurand(source loading) E: Potentiometer for angle measurements. Modulating sensors: Measure desired quantity by modulating Additional source with modulated energy. Also

adds error. E: Non0contact displacement measrement (rotating disk)

Analog vs. Digital:

Analog: time and value continuous

Digital: Discrete outputs **Deflection mode sensors:**

Response to an output is a deviation from the equilibrium position

Null mode sensors:

Sensor or instruments exert an influence the measured system opposing the effect of the measurand. Ideally the result is a 0 measurement, typically achieved by feedback. The opposing influence is then the sensor

output. Slower than deflection, but more accurate.

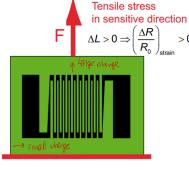
Resistive sensors - strain gauges

Change in geometry under mechanical stress produces associated resistance change Volum. == const. \rightarrow

Volume 3- Const.
$$\rightarrow \frac{\partial V}{V_0} = \frac{L_0}{V_0} \cdot \partial A + \frac{A_0}{V_0} \cdot \partial L \wedge \frac{\partial V}{V_0} = 0 \Rightarrow \frac{\partial A}{A_0} = -\frac{\partial L}{L_0} \rightarrow \frac{\partial R}{R_0} = \frac{\partial \rho}{\rho_0} + 2\frac{\partial L}{L_0} \rightarrow \frac{\partial R}{R_0} = \alpha \cdot \frac{\partial L}{L_0} + 2\frac{\partial L}{L_0} = \underbrace{(\alpha + 2)}_{\underline{A}L} \cdot \frac{\partial L}{L_0}$$

k: gauge factor

 α proportionality factor $\frac{\partial \rho}{\rho_0} \propto \frac{\partial L}{L_0}$



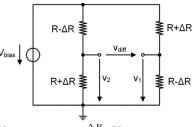
Readout resistive sensors

Use a half bridge resistive divider top element sensing resistor

$$rac{v_{
m out}}{V_{
m bias}} = rac{R}{2R + \Delta R} \Leftrightarrow rac{\Delta R}{R} = rac{V_{
m bias}}{v_{
m out}} - 2$$
 Full bridge to remove offset, 2 sensing

elements more sensitive. remove nonlinearity by implementing

differential measurements Best use 4point full bridge



 $V_{
m diff}=v_2-v_1=rac{\Delta R}{R}\cdot V_{
m bias}$ Sensitivity S=45mV/V excitation for 1V

Accuracy $A = \frac{v_{\mathrm{diff}}\left(\frac{\Delta R}{R}\right) - V_{\mathrm{diff},\ln}\left(\frac{\Delta R}{R}\right)}{V_{\mathrm{diff}}\left(\frac{\Delta R}{R}\right)}$ Deviation from the ideal bridge

BridgeParameters

Bridge resistance: Unloaded R across the signal terminals

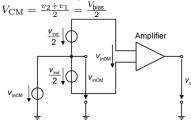
Offset error Outputvoltage at 0 input **Drift:** Outputchange conditioned on environmental condition

Differential/ Commonmode signals

Recall: $V_1 = \frac{1}{2} \cdot \left(1 - \frac{\Delta R}{R}\right) \cdot V_{\text{bias}}$, $v_2 =$ $\frac{1}{2} \cdot \left(1 + \frac{\Delta R}{R}\right) \cdot V_{\text{bias}}$

Differential signal:

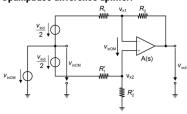
 $V_{\mathrm{diff}} = V_2 - V_1 = \frac{\Delta R}{R} \cdot V_{\mathrm{bias}}$ Common-mode signal:



DiffGain: $V_{\text{out}} = A_{\text{DM}} \cdot V_{\text{inDM}}$ CMMGain: $V_{\mathrm{out}} = A_{\mathrm{CM}} \cdot v_{\mathrm{inCM}}$ Ideally A_{cm} is 0 or $A_{cm} \ll A_{dm}$ Commonmode rejection ratio(CMRR): $CMRR \triangleq \left| \frac{A_{DM}}{A_{CM}} \right| = \left| \frac{dv_{out}/dv_{inDM}}{dv_{out}/dv_{inCM}} \right|$

Often in dB

Opampbase difference aplifier:



1st: $A(s)=\infty, R_2=R_2'=\alpha\cdot R_1=\alpha R_1'$ $A_{DM}=-\alpha, A_{CM}=0, CMRR=\infty$ $2^{\rm nd}$ assume $A(s)=\infty, R_2=\alpha\cdot R_1,$ $R_2' = (\alpha + \Delta \alpha) \cdot R_1', R_1' = R_1 + \Delta R$
$$\begin{split} & A_{\mathrm{DM}} = -\left(\alpha + \frac{\Delta\alpha}{2\cdot(1+\alpha+\Delta\alpha)}\right) \\ & A_{\mathrm{CM}} = \frac{\Delta\alpha}{1+\alpha+\Delta\alpha} \\ & \mathrm{CMRR} = -\frac{1}{2} + \frac{\alpha\cdot(1+\alpha+\Delta\alpha)}{\Delta\alpha} \\ & 3d: A(s) = A_{\mathrm{DC}}/\left(1+s\cdot\frac{A_{\mathrm{DC}}}{\mathrm{GBW}}\right) \end{split}$$
 $A_{\rm DM} = -\left(\alpha + \frac{\Delta\alpha}{2 \cdot (1 + \alpha + \Delta\alpha)}\right) \cdot \frac{1}{1 + \frac{1}{A_{\rm DC}} + \frac{\alpha}{A_{\rm DC}} + (1 + \alpha) \cdot \frac{s}{\rm GBW}}$ $\begin{aligned} & A_{\text{CM}} = \\ & \frac{\Delta \alpha}{1 + \alpha + \Delta \alpha} \cdot \frac{1}{1 + \frac{1}{A_{\text{DC}}} + \frac{\alpha}{A_{\text{DC}}} + (1 + \alpha) \cdot \frac{s}{\text{GBW}}} \\ & \text{CMRR} = -\frac{1}{2} + \frac{\alpha \cdot (1 + \alpha + \Delta \alpha)}{\Delta \alpha} \end{aligned}$

Magnetic Field Sensors

 $V_{ ext{hall}} = G \cdot rac{\mu \cdot
ho}{h} \cdot l \cdot B = G \cdot rac{1}{e \cdot n \cdot h} \cdot l \cdot B = S_l \cdot l \cdot B$ G: geometry factor **Noise sources:**

- Thermal noise
- -1/f noise

-Noise of conditioning electronics

Noise power: $V_{noise} \sqrt{4kT \cdot R \cdot \Delta f}$ Signal power: $V_{hall}S_I \cdot I \cdot B$

Resolution: $B_{\min} \hat{\wedge} \frac{V_{\text{noise}}}{V_{\text{hall}} / B} = \frac{\sqrt{4kT \cdot R \cdot \Delta f}}{S_l \cdot I}$ With $S_I=rac{\mu\cdot\rho}{h\cdot e\cdot n}\cdot G$ At B=0 Hall plate can be modeled as

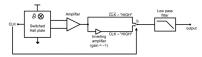
wheatstone bridge, non-uniform stress causes intrinsic offset(5 to 30mT)

Cancel intrinsic offset by coupling ° turned sensors, current and sense ports are swapped Idea: Hall voltage is in phase and gradient caused offsets are than 180° out of phase Spinning current method:

Sense and current ports are switched every clock cycle

Idea: A DC component equal to the offset and a frequency component proportional to the hall voltage is produced (Fourier Expansion of a square wave)

By modulating the information to the clock frequency noise and offset are greatly mitigated.



Multiplying by 1 and -1 to demodulate back to low frequency.

Low pass stage to remove signal around the 2nd harmonic

This allow to see the base noise floor of the sensor not 1/f noise.

In the conventional implementation 2 bias currents are used in the low power configuration the bias form the plate is reused for the amplifier.

Temperature Sensors

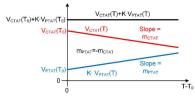
Seebeck effect: Convert temp. gradient to electromotive force

F(T)=
$$\int_{T_{stand.}}^{T} (S_{+}(T') - S_{-}(T'))dT'$$

 $\rightarrow E_{emf} = F(T_{sense} - F(T_{ref}))$

Temperature stable references:

$$V_{\mathrm{REF}}(T) = V_{\mathrm{CTAT}}(T) + K \cdot V_{\mathrm{PTAT}}(T)$$
 Bandgap reference:



PTAT: Proportional to absolute temperature CTAT: Complementary to absolute temperature Scale one slope and add the function for a temp, constant reference This can be built with a diode or a BJT with a shorted base and collector

Butt current is also temperature dependent so

use diff pair. $\begin{array}{l} V_{\mathrm{PTAT}} \stackrel{.}{=} \Delta V_{\mathrm{EB}} = V_{\mathrm{EB1}} - V_{\mathrm{EB2}} \approx \\ \frac{kT}{q} \cdot \ln \left[\frac{I_q \cdot I_S' \cdot A_{E2}}{I_S' \cdot A_{E1} \cdot I_q} \right] = \frac{kT}{q} \cdot \ln \left[\frac{A_{E2}}{A_{E1}} \right] \end{array}$ Scale currents or diodes to make equal bias

$$V_{\rm EB} = \underbrace{E_g/q}_{V_G} - \underbrace{\frac{kT}{q}}_{U_T} \cdot \ln\left(\frac{I_s'}{I_D}\right) =$$

$$V_G - U_T \cdot \ln\left(\frac{K_1 \cdot T^{\gamma}}{I_D}\right)$$
$$V_G \approx V_{G0K} - a \cdot T$$

With $I_S^\prime > I_D$ but also temperature dependent \rightarrow curved CTAT.

Combine CTAT and PTAT: Series:

$$\begin{aligned} V_{\text{REF}} &= I_{\text{PTAT}} \cdot R_2 + V_{\text{CTAT}} = \\ \frac{R_2}{R_1} \cdot V_{\text{PTAT}} + V_{\text{CTAT}} \end{aligned}$$

Parallel:

$$\begin{array}{l} V_{\mathrm{REF}} = \left(I_{\mathrm{PTAT}} + I_{\mathrm{CTAT}}\right) \cdot R_{3} = \\ \frac{R_{3}}{R_{1}} \cdot V_{\mathrm{PTAT}} + \frac{R_{3}}{R_{2}} \cdot V_{\mathrm{CTAT}} \end{array}$$